

**Search Notes**

Application/Control No.

10/699,117

Examiner

Tae H. Yoon

Applicant(s)/Patent under  
Reexamination

PARK ET AL.

Art Unit

1714

**SEARCHED**

Class	Subclass	Date	Examiner
523	116	1-13-06	ry
	120		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	1-13-06	ry
Inventor Search	1-21-06	ry